

FMOS試験観測のデータ解析(III): 輝線フラックスのS/N評価

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Abstract

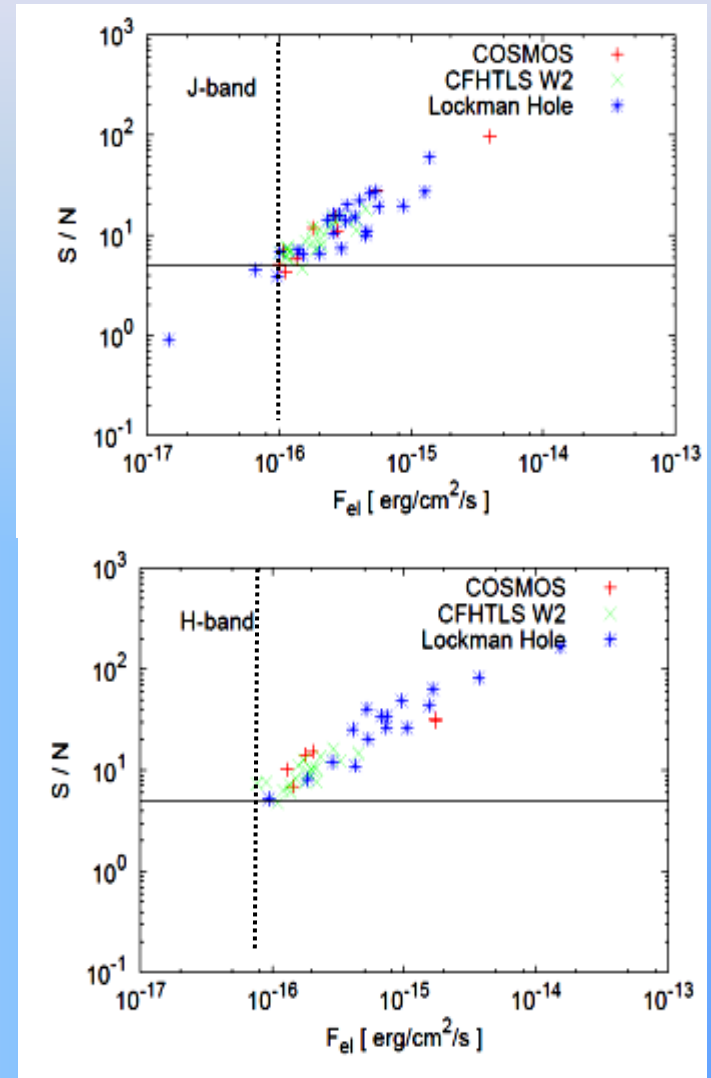
- We analyze FMOS ER data in Dec. 2009, and...
 - Check FMOS spectra including emission-line.
 - Estimate FMOS emission-line sensitivity.
 - Discuss uncertainties of redshift measured from emission-line detected by FMOS.

FMOS Feasibility Study (Emission Line)

- Data Set:
 - COSMOS: exp. time = 45min (BS-mode)
 - CFHTLS W2: exp. time = 90min (BS-mode)
 - Lockman Hole: exp. Time = 90min (CBS-mode)
 - Data Analysis:
 - Estimate emission-line flux by Gaussian-fitting
 - Only use data in J-band ($\lambda=1.1-1.35$) & H-band ($\lambda=1.4-1.7$), because of less sensitivities
 - Estimate noise by using 1d-spectra around emission-line
- ⇒ Estimate S/N of emission-line !!

Emission-Line Sensitivity

- FMOS sensitivity (1hr, S/N=5)
 - J: 1.0×10^{-16} erg/cm²/s
 - H: 0.9×10^{-16} erg/cm²/s



Redshift Uncertainty

- Redshift dispersion is due to resolution ($R=500$).

